

Towards parametric model order reduction for nonlinear PDE systems in networks

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Outline

Motivation

PDAE-model

Finite Element Method

Simulation results

Construction of the reduced model

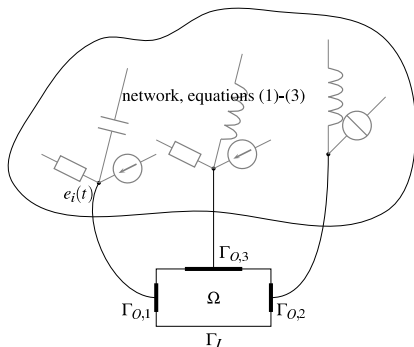
Location dependence of reduced model

Residual based parameter sampling

PABTEC and POD, joint work with A. Steinbrecher & Tatjana Stykel

Next steps

Motivation: Coupled circuit and semiconductor models



Aim

- ▶ Accurate reduced order models for semiconductors in networks
- ▶ Validity over relevant parameter range
- ▶ Accurate *physical* reduced order model of the coupled system

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Coupled circuit and semiconductor models [M. Günther '01, C. Tischendorf '03]

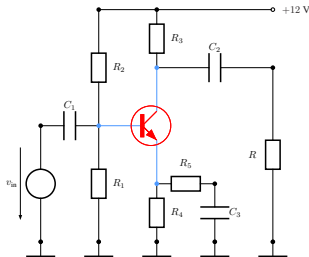
Kirchhoff's' laws (no semiconductors) read

$$A_j = 0, \quad v = A^T e$$

A : incidence matrix.

Voltage-current relations of components:

$$j_C = \frac{dq_C}{dt}(v_C, t), \quad j_R = g(v_R, t), \quad v_L = \frac{d\phi_L}{dt}(j_L, t)$$



Modified Nodal Analysis: join all equations to DAE system

$$A_C \frac{dq_C}{dt} (A_C^T e(t), t) + A_R g (A_R^T e(t), t) + A_L j_L(t) + A_V j_V(t) = -A_I i_s(t),$$

$$\frac{d\phi_L}{dt} (j_L(t), t) - A_L^T e(t) = 0,$$

$$A_V^T e(t) = v_s(t).$$

Coupled circuit and semiconductor models [M. Günther '01, C. Tischendorf '03]

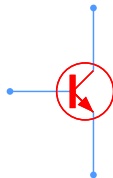
How can semiconductors be introduced?

- ▶ replace semiconductor by a (possibly nonlinear) electrical network,
- ▶ stamp semiconductor network into surrounding network,
- ▶ apply Modified Nodal Analysis.
- ▶ Here: use PDE model for semiconductors \rightarrow DD equations.

Coupled circuit and semiconductor models [M. Günther '01, C. Tischendorf '03]

PDE-model (drift-diffusion equations) for semiconductors

$$\begin{aligned} \operatorname{div}(\varepsilon \nabla \psi) &= q(n - p - C), \\ -q \partial_t n + \operatorname{div} J_n &= qR(n, p), \\ q \partial_t p + \operatorname{div} J_p &= -qR(n, p), \\ J_n &= \mu_n q (-U_T \nabla n - n \nabla \psi), \\ J_p &= \mu_p q (-U_T \nabla p - p \nabla \psi), \end{aligned}$$



on $\Omega \times [0, T]$ with $\Omega \subset \mathbb{R}^d$ ($d = 1, 2, 3$).

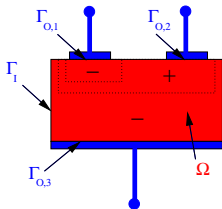
Dirichlet boundary constraints at $\Gamma_{O,k}$:

$$\psi(t, x) = \text{next slide}, \quad n(t, x) = \tilde{n}(x), \quad p(t, x) = \tilde{p}(x)$$

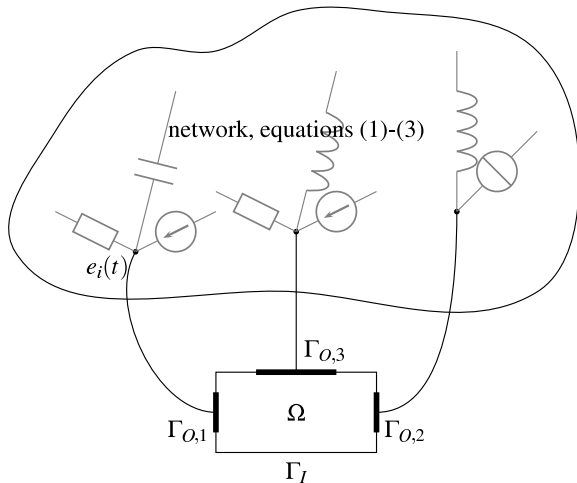
and Neumann boundary constraints at Γ_I :

$$\nabla \psi(t, x) \cdot \nu(x) = J_n \cdot \nu(x) = J_p(t, x) \cdot \nu(x) = 0$$

or mixed boundary conditions at MI contacts (MOSFETs).



Couple semiconductor to circuit [M. Günther '01, C. Tischendorf '03]



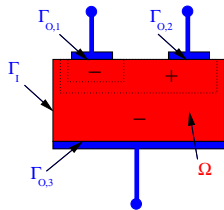
Couple semiconductor to circuit [M. Günther '01, C. Tischendorf '03]

Coupling conditions:

$$j_{S,k}(t) = \int_{\Gamma_{O,k}} (J_n + J_p - \varepsilon \partial_t \nabla \psi) \cdot \nu \, d\sigma,$$

$$\psi(t, x) = \psi_{bi}(x) + (A_S^T e(t))_k$$

for $(t, x) \in [0, T] \times \Gamma_{O,k}$,



and add current j_S to Kirchhoff's current law:

$$A_C \frac{dq_C}{dt} (A_C^T e, t) + A_{RG} (A_R^T e, t) + A_L j_L + A_V j_V + A_S j_S = -A_I i_S,$$

$$\frac{d\phi_L}{dt} (j_L, t) - A_L^T e = 0,$$

$$A_V^T e = v_S.$$

Add DD-equations + coupling conditions for each semiconductor.

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Mixed formulation

The electric field $E = -\nabla\psi$ plays dominant role in DD-equations.

Mixed formulation

[Brezzi et al. '05]

Provide additional variable g_ψ and equation

$$g_\psi = \nabla\psi.$$

Scaled DD equations then read:

$$\begin{aligned} \lambda \operatorname{div} g_\psi &= n - p - C, \\ -\partial_t n + \nu_n \operatorname{div} J_n &= R(n, p), \\ \partial_t p + \nu_p \operatorname{div} J_p &= -R(n, p), \\ g_\psi &= \nabla\psi, \\ J_n &= \nabla n - n g_\psi, \\ J_p &= -\nabla p - p g_\psi. \end{aligned}$$

Finite Element approximation

Finite elements

- ▶ piecewise constant ansatz functions for ψ , n and p .
Basis functions: φ_i , $i = 1, \dots, N$, $N = |\mathcal{T}|$.
- ▶ Raviart-Thomas elements for g_ψ , J_n and J_p .
Basis functions: ϕ_j , $i = 1, \dots, M$, $M = |\mathcal{E}| - |\mathcal{E}_N|$.

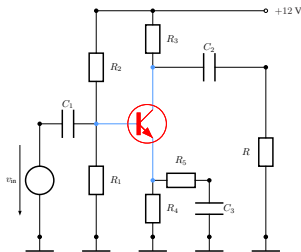
$$RT_0 := \{y : \Omega \rightarrow \mathbb{R}^d : y|_T(x) = a_T + b_T x, a_T \in \mathbb{R}^d, b_T \in \mathbb{R}, [y]_E \cdot \nu_E = 0, \text{ for all inner edges } E\}.$$

Galerkin ansatz:

$$\psi^h(t, x) = \sum_{i=1}^N \psi_i(t) \varphi_i(x), \quad g_\psi^h(t, x) = \sum_{j=1}^M g_{\psi,j}(t) \phi_j(x),$$

and analogously for n , p , J_n , and J_p .

Full model



$$\begin{aligned}
 A_C \frac{dq_C}{dt} (A_C^T e(t), t) + A_{RG} (A_R^T e(t), t) \\
 + A_{Lj_L}(t) + A_{Vj_V}(t) + A_S j_S(t) = -A_I i_S(t), \\
 \frac{d\phi_L}{dt} (j_L(t), t) - A_L^T e(t) = 0, \\
 A_V^T e(t) = v_S(t),
 \end{aligned}$$

$$j_S(t) - C_1 j_n(t) - C_2 j_p(t) - C_3 \dot{g}_\psi(t) = 0,$$

$$\begin{pmatrix} 0 \\ -M_L \dot{n}(t) \\ M_L \dot{p}(t) \\ 0 \\ 0 \\ 0 \end{pmatrix} + A_{FEM} \begin{pmatrix} \psi(t) \\ n(t) \\ p(t) \\ g_\psi(t) \\ j_n(t) \\ j_p(t) \end{pmatrix} + \mathcal{F}(n^h, p^h, g_\psi^h) - b(A_S^T e(t)) = 0.$$

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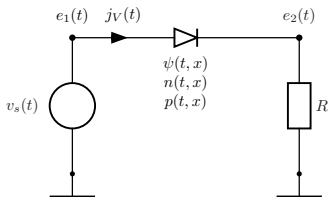
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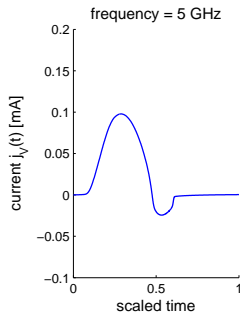
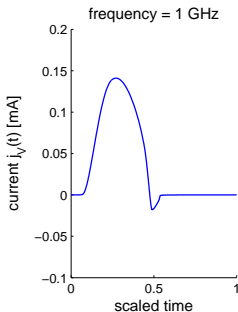
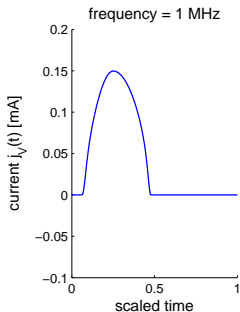
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Basic test circuit, simulation results



input voltage: $v_s(t) = 5[V] \cdot \sin(2\pi f \cdot t)$
 similar results obtained by MECS [Selva Soto]



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Snapshot-POD (Proper Orthogonal Decomposition) [L. Sirovich '87]

Full simulation yields snapshots (here: $y = \psi, n, p, \dots$)

$$\{y(t_i, \cdot)\}_{i=1, \dots, m} \subset \text{span}\{\varphi_j\}_{j=1, \dots, N}, \quad \text{with} \quad y(t_i, x) = \sum_{j=1}^N \tilde{y}_j(t_i) \varphi_j(x).$$

Gather coefficients in matrix

$$Y := (\vec{y}(t_1), \dots, \vec{y}(t_m)) \in \mathbb{R}^{N \times m}.$$

POD in Hilbert space X as eigenvalue problem:

$$Kv^k = \sigma_k^2 v^k, \quad \text{with} \quad K_{ij} := \langle y(t_i, \cdot), y(t_j, \cdot) \rangle_X.$$

Note that $K = Y^T M Y$ with $M_{ij} = \langle \varphi_i, \varphi_j \rangle_X$. Write POD in terms of SVD:

$$\tilde{U} \Sigma \tilde{V}^T = L^T Y, \quad \text{with} \quad L L^T := M.$$

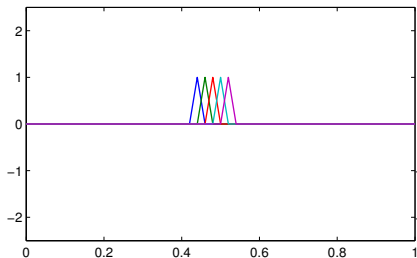
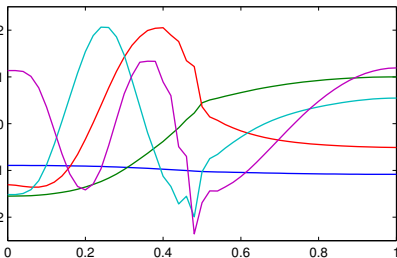
Then, the s -dimensional POD basis is

$$\left\{ u^i := \sum_{j=1}^N \tilde{u}_j^i \varphi_j(\cdot) \right\}_{i=1, \dots, s}, \quad U := (\tilde{u}^1, \dots, \tilde{u}^s) := L^{-T} \tilde{U}_{(:, 1:s)}.$$

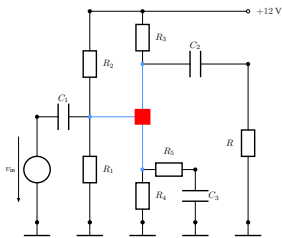
Model Order Reduction

- ▶ Simulate the complete network at one or more reference parameters.
- ▶ Take snapshots of the state of each semiconductor at time points t_i .
- ▶ Perform POD **component wise** on ψ , n , p , g_ψ , J_n and J_p .
- ▶ Use the POD basis functions as (non local) FEM ansatz functions:

$$\psi^{POD}(t, x) = \sum_{i=1}^s \gamma_{\psi,i}(t) u_{\psi}^i(x)$$

 1D-FEM ansatz functions for J_n

 first 5 POD basis functions for J_n


Reduced model



$$A_C \frac{dq_C}{dt} (A_C^T e(t), t) + A_{Rg} (A_R^T e(t), t) \\
+ A_L j_L(t) + A_V j_V(t) + A_S j_S(t) = -A_I i_S(t), \\
\frac{d\phi_L}{dt} (j_L(t), t) - A_L^T e(t) = 0, \\
A_V^T e(t) = v_S(t),$$

$$j_S(t) - C_1 U_{J_n} \gamma_{J_n}(t) - C_2 U_{J_p} \gamma_{J_p}(t) - C_3 U_{g_\psi} \dot{\gamma}_{g_\psi}(t) = 0,$$

$$\begin{pmatrix} 0 \\ -\dot{\gamma}_n(t) \\ \dot{\gamma}_p(t) \\ 0 \\ 0 \\ 0 \end{pmatrix} + A_{POD} \begin{pmatrix} \gamma_\psi(t) \\ \gamma_n(t) \\ \gamma_p(t) \\ \gamma_{g_\psi}(t) \\ \gamma_{J_n}(t) \\ \gamma_{J_p}(t) \end{pmatrix} + U^T \mathcal{F}(n^{POD}, p^{POD}, g_\psi^{POD}) - U^T b(A_S^T e(t)) = 0.$$

Computational complexity

Computational complexity of reduced model still depends on n_{FEM} :

$$U^T \mathcal{F}(n^{POD}, p^{POD}, g_{\psi}^{POD}) = \underbrace{U^T}_{n_{POD} \times n_{FEM}} \underbrace{F}_{n_{FEM}} \left(\underbrace{U_n}_{n_{FEM} \times n_{POD}}, \gamma_n, U_p \gamma_p, U_{g_{\psi}} \gamma_{g_{\psi}} \right).$$

With matrix-matrix multiplications in Jacobian computation:

$$\underbrace{U^T}_{n_{POD} \times n_{FEM}, \text{ block-dense}} \underbrace{F'(\dots)}_{n_{FEM} \times n_{FEM}, \text{ sparse}} \underbrace{U}_{n_{FEM} \times n_{POD}, \text{ block-dense}}.$$

Discrete Empirical Interpolation Md. (DEIM) [S. Chaturantabut, D. Sorensen '09]

DEIM

- ▶ Do POD on snapshots $\{F(n(t_i), p(t_i), g_{\psi}(t_i))\}$, obtain basis $W \in \mathbb{R}^{n_{FEM} \times n_{DEIM}}$ (block diagonal matrix).

- ▶ Ansatz

$$F(U_n \gamma_n(t), U_p \gamma_p(t), U_{g_{\psi}} \gamma_{g_{\psi}}(t)) \approx Wc(t)$$

is overdetermined.

- ▶ Select n_{DEIM} “useful” rows:

$$P^T F(\dots) \approx P^T Wc(t).$$

- ▶ If $P^T W$ is regular:

$$F(\dots) \approx Wc(t) = W(P^T W)^{-1} P^T F(\dots)$$

The regularity of $P^T W$ can be guaranteed, see [CS09].
 Again we apply the method **component-wise**.

Discrete Empirical Interpolation Md. (DEIM) [S. Chaturantabut, D. Sorensen '09]

Reduced model

$$U^T F(U_n \gamma_n, U_p \gamma_p, U_{g_\psi} \gamma_{g_\psi})$$

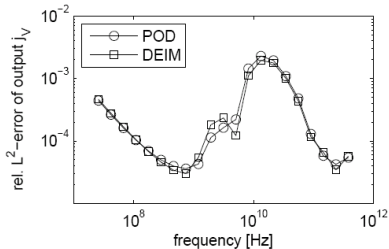
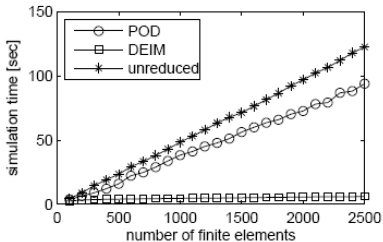
with DEIM:

$$\underbrace{(U^T W (P^T W)^{-1})}_{n_{POD} \times n_{DEIM}, \text{ block-dense}} \underbrace{P^T F(U_n \gamma_n, U_p \gamma_p, U_{g_\psi} \gamma_{g_\psi})}_{\substack{n_{DEIM} \\ n_{FEM}}}$$

Results for 1D-diode:

	n_{FEM}	FEM	n_{POD}	ROM	n_{DEIM}	ROM + DEIM
	3003	3.15 sec.	220	3.52 sec.	187	1.93 sec.
	15009	23.5 sec.	229	19.9 sec.	198	4.04 sec.
	48015	82.3 sec.	229	74.2 sec.	199	9.87 sec.
order		$\approx n_{FEM}^{1.18}$		$\approx n_{FEM}^{1.10}$		$\approx n_{FEM}^{0.578}$

Discrete Empirical Interpolation Md. (DEIM) [S. Chaturantabut, D. Sorensen '09]



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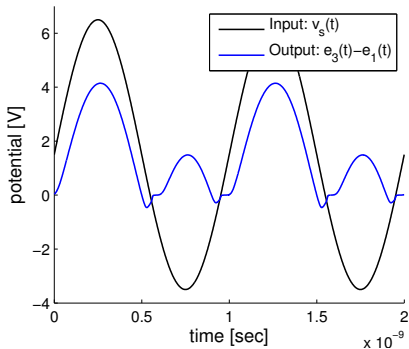
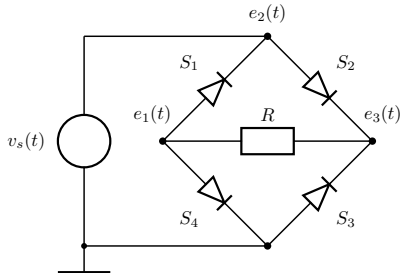
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Next steps

Reduced model depends on position of diode in network

Bridge rectifier with 4 diodes:



Reduced model depends on position of diode in network

The distance between the spaces U^1 and U^2 which are spanned, e.g., by the POD-functions U_{ψ}^1 of the diode S_1 and U_{ψ}^2 of the diode S_2 respectively, is measured by

$$d(U^1, U^2) := \max_{\substack{u \in U^1 \\ \|u\|_2=1}} \min_{\substack{v \in U^2 \\ \|v\|_2=1}} \|u - v\|_2 = \sqrt{2 - 2\sqrt{\lambda}},$$

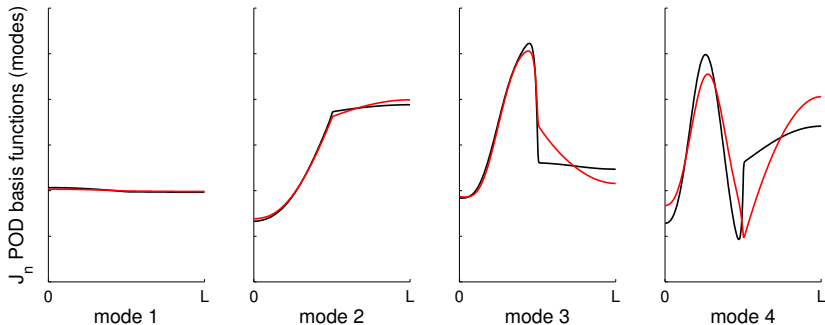
where λ is the smallest eigenvalue of the positive definite matrix SS^T with $S_{ij} = \langle u_{\psi,i}^1, u_{\psi,j}^2 \rangle_2$.

Δ	$d(U^1, U^2)$	$d(U^1, U^3)$
10^{-4}	0.61288	$5.373 \cdot 10^{-8}$
10^{-5}	0.50766	$4.712 \cdot 10^{-8}$
10^{-6}	0.45492	$2.767 \cdot 10^{-7}$
10^{-7}	0.54834	$1.211 \cdot 10^{-6}$

Table: Distances between reduced models in the rectifier network.

Modes

MOR yields a similar but different model for the diodes S_1 and S_2 :



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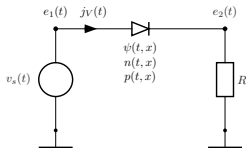
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Problem setting

MOR test problem

Basic circuit with **frequency f** of the voltage source $v_s(t) = 5[V] \cdot \sin(2\pi f \cdot t)$ as **model parameter**.

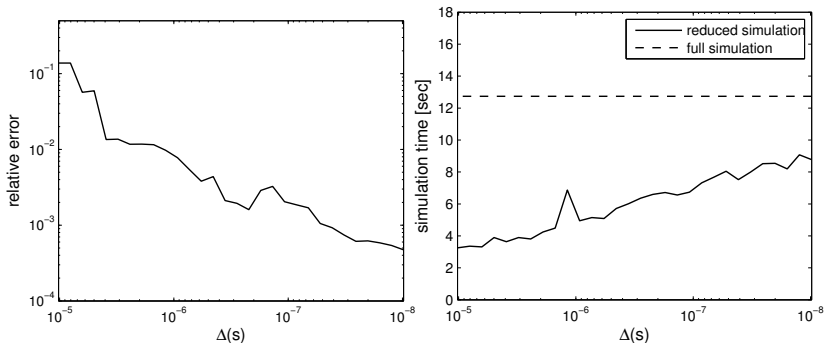


Lack of information

Select number of snapshots so that $\Delta(s) = \sqrt{\frac{\sum_{i=s+1}^m \sigma_i^2}{\sum_{i=1}^m \sigma_i^2}} \approx \text{tol}$.

Reduced model at a fixed frequency

First test: Compare reduced and unreduced system at a fixed frequency.

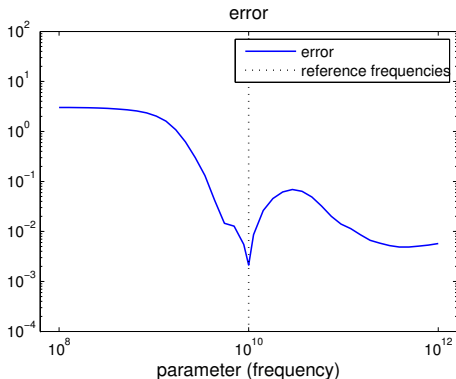


Reduced model over parameter space

Construction of reduced model requires snapshots from full simulations at reference parameters.

Is the model valid over a large parameter space?

reference parameter: $P_1 := \{f_1\} := \{10^{10}[\text{Hz}]\}$
 parameter space $\mathcal{P} = [10^8, 10^{12}]$



Reduced model over parameter space - sampling

Goal

Find new sampling parameter f_{k+1} (reference frequency) without simulating the full, unreduced system. Set $P_{k+1} := P_k \cup \{f_{k+1}\}$.

- ▶ We do not consider the PDE discretization error.
- ▶ Rigorous upper bound for the error not available

$$\|\mathcal{E}(f; P_k)\| = \|y^h(f) - y^{POD}(f; P_k)\| \leq ?(s)$$

where $y^h := (\psi^h, n^h, p^h, g_\psi^h, J_n^h, J_p^h)^\top$, $y^{POD} := (\psi^{POD}, n^{POD}, \dots)^\top$.

- ▶ Rigorous RB methods, Greedy algorithm [see e.g. A. Patera, G. Rozza '07]: a-posteriori error estimates required.
- ▶ Linear ODEs [see e.g. B. Haasdonk, M. Ohlberger '09]: build difference between residual and unreduced equation to derive an ODE for the error.

Residual based sampling

Define residual $\mathcal{R}(z^{POD}(f; P_k))$: insert $z^{POD}(f; P_k)$ into unreduced equation,

$$\mathcal{R} := \begin{pmatrix} 0 \\ -M_L \dot{n}^{POD}(t) \\ M_L \dot{p}^{POD}(t) \\ 0 \\ 0 \\ 0 \end{pmatrix} + A_{FEM} \begin{pmatrix} \psi^{POD}(t) \\ n^{POD}(t) \\ p^{POD}(t) \\ g_{\psi}^{POD}(t) \\ J_n^{POD}(t) \\ J_p^{POD}(t) \end{pmatrix} + \mathcal{F}(n^{POD}, p^{POD}, g_{\psi}^{POD}) - b(e^{POD}(t)).$$

Residual admits different scales.

Scale with block diagonal matrix-valued function

$$D(f) := \text{diag}(d_{\psi}(f)I, d_n(f)I, d_p(f)I, d_{g_{\psi}}(f)I, d_{J_n}(f)I, d_{J_p}(f)I)$$

and choose $d_{\psi}(f)$ according to

$$d_{\psi}(f_j) \cdot \|\mathcal{R}_{\psi}(y^{POD}(f_j; P_k))\| = \frac{\|\psi^h(f_j) - \psi^{POD}(f_j; P_k)\|}{\|\psi^h(f_j)\|}, \quad \forall f_j \in P_k.$$

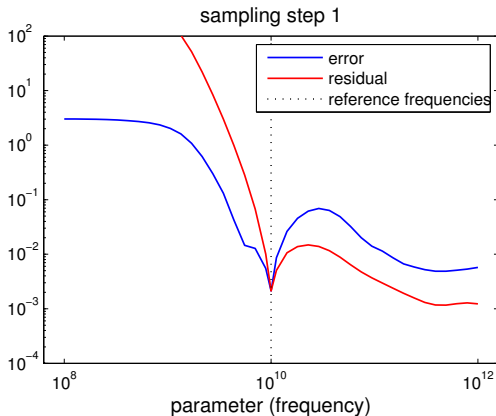
Residual based sampling

Algorithm: sampling

1. Select $f_1 \in \mathcal{P}$, $P_{test} \subset \mathcal{P}$, $tol > 0$, and set $k := 1$, $P_1 := \{f_1\}$.
2. Simulate the unreduced model at f_1 and calculate the reduced model with POD basis functions U_1 .
3. Calculate weight functions $d_{(\cdot)}(f) > 0$ for all $f \in P_k$.
4. Calculate the scaled residual $\|D(f)\mathcal{R}(z^{POD}(f, P_k))\|$ for all $f \in P_{test}$.
5. Check termination conditions, e.g.
 - ▶ $\max_{f \in P_{test}} \|D(f)\mathcal{R}(z^{POD}(f, P_k))\| < tol$,
 - ▶ no progress in weighted residual.
6. Calculate $f_{k+1} := \arg \max_{f \in P_{test}} \|D(f)\mathcal{R}(z^{POD}(f, P_k))\|$.
7. Simulate the unreduced model at f_{k+1} and create a new reduced model with POD basis U_{k+1} using also the already available information at f_1, \dots, f_k .
8. Set $P_{k+1} := P_k \cup \{f_{k+1}\}$, $k := k + 1$ and goto 3.

Numerical example - sampling step 1

Let $f_1 := 10^{10}[\text{Hz}]$, $P_1 := \{10^{10}[\text{Hz}]\}$, $\mathcal{P} = [10^8, 10^{12}]$.

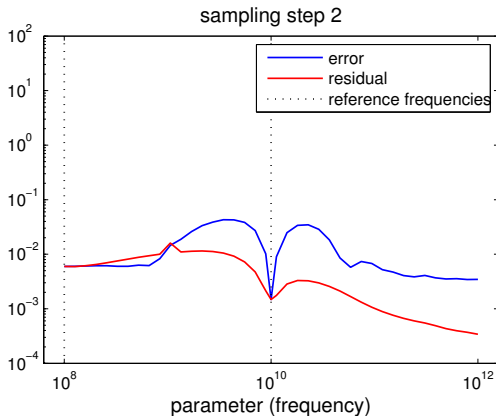


$$f_2 = \arg \max_{f \in P_{\text{test}}} \|D(f)\mathcal{R}(z^{\text{POD}}(f, P_1))\| = 10^8[\text{Hz}]$$

$$P_2 = \{10^8[\text{Hz}], 10^{10}[\text{Hz}]\}$$

Numerical example - sampling step 2

$$P_2 = \{10^8[\text{Hz}], 10^{10}[\text{Hz}]\}$$

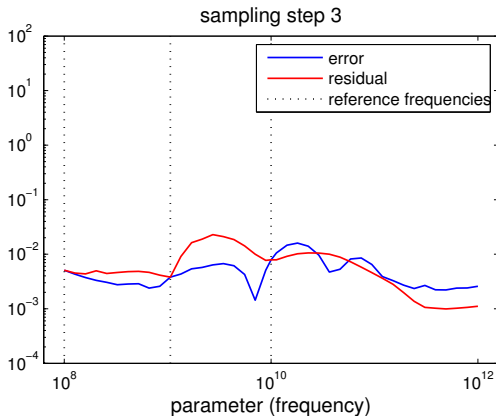


$$f_3 = \arg \max_{f \in P_{\text{test}}} \|D(f)\mathcal{R}(z^{\text{POD}}(f, P_2))\| = 1.0608 \cdot 10^9[\text{Hz}]$$

$$P_3 = \{10^8[\text{Hz}], 1.0608 \cdot 10^9[\text{Hz}], 10^{10}[\text{Hz}]\}$$

Numerical example - sampling step 3

$$P_3 = \{10^8[\text{Hz}], 1.0608 \cdot 10^9[\text{Hz}], 10^{10}[\text{Hz}]\}$$



Terminate with “no progress in residual”.

Outline

Motivation

PDAE-model

Finite Element Method

Simulation results

Construction of the reduced model

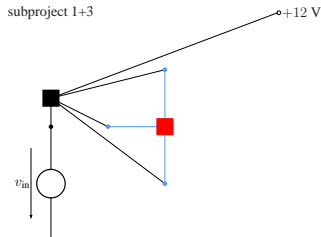
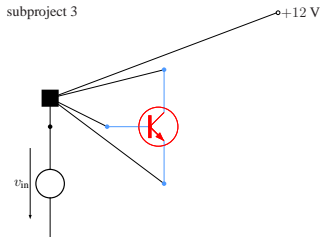
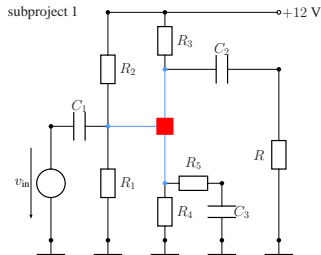
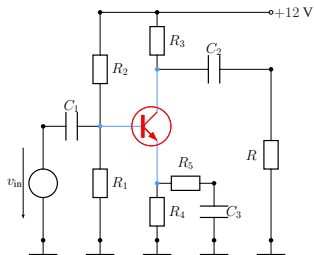
Location dependence of reduced model

Residual based parameter sampling

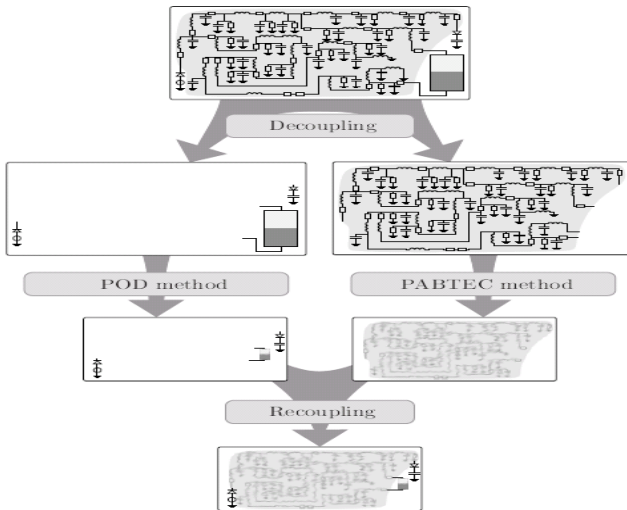
PABTEC and POD, joint work with A. Steinbrecher & Tatjana Stykel

Next steps

Combination of PABTEC (Reis & Stykel 2010) and POD; joint work with [A. Steinbrecher, T. Stykel]



Combination of PABTEC and POD; Int. J. Numer. Model. 2012



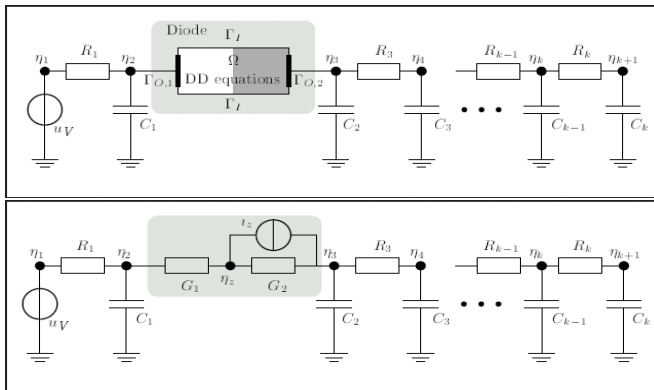
Substitution of nonlinear components for PABTEC and recoupling

A. Steinbrecher, T. Stykel (Int. J. Circuits Theory Appl., 2012):

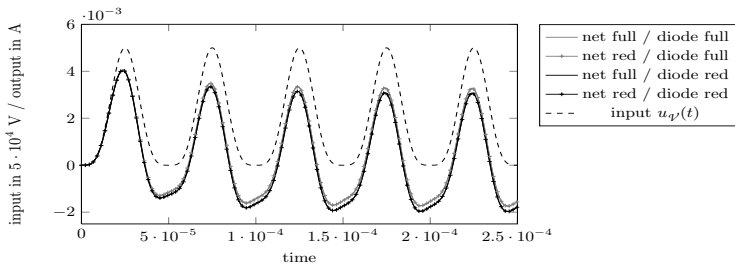
Nonlinear inductor \rightarrow current source

Nonlinear capacitor \rightarrow voltage source

Nonlinear resistor \rightarrow linear circuit with 2 serial resistors and one voltage source parallel to one of the resistors



Combination of PABTEC and POD; Int. J. Numer. Model. 2012



network (MNA equations)		diode (DD equations)		coupled system dim.	simul. time	Jacobian evaluations	absolute error $\ y - \hat{y}\ _{L_2}$	relative error $\frac{\ y - \hat{y}\ _{L_2}}{\ y\ _{L_2}}$
type	dim.	type	dim.					
unreduced	1503	unreduced	6006	7510	23.37s	20		
reduced	24	unreduced	6006	6031	16.90s	17	$2.165 \cdot 10^{-8}$	$7.335 \cdot 10^{-4}$
unreduced	1503	reduced	105	1609	1.51s	16	$2.952 \cdot 10^{-6}$	$1.000 \cdot 10^{-1}$
reduced	24	reduced	105	130	1.19s	11	$2.954 \cdot 10^{-6}$	$1.000 \cdot 10^{-1}$

Next steps

- ▶ Include QDD models.
- ▶ Include EM effects.
- ▶ Generalize approach to other equation networks containing simple and complex components.

Thank you for attending!



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